



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#15/2856
B
V. Brown
3/21/03

In re Application of)
Hans-Ulrich Krotil et al.)
Serial No.: 09/869,789) Group:
Filed: July 23, 2002)
Title: METHOD AND DEVICE FOR SIMULTANEOUSLY)
DETERMINING THE ADHESION, FRICTION, AND)
OTHER MATERIAL PROPERTIES OF A SAMPLE)

**PRELIMINARY AMENDMENT DELETING
MULTIPLE DEPENDENT CLAIMS**

Assistant Commissioner of Patents
Washington, DC 20231

Sir:

Prior to calculating the filing fee, please enter the following amendments to the application.

IN THE CLAIMS

Please amend claims 3, 5, 7, 9, 11, 13, 17, 19, 21, 23-25, and 27 as follows:

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B1

3. Raster probe microscope according to claim 1,
characterized by periodic raster-probe and/or sample oscillations.

B2

5. Raster probe microscope according to claim 3,
characterized in that,
the vertical oscillation of the raster probe (1) and/or of the sample (25) occurs with a first
frequency of at least 10 Hz and a first amplitude of at least 1 nm.

B3

7. Raster probe microscope according to claim 5,
characterized in that,
the vertical oscillation of the raster probe (1) and/or of the sample (25) is additionally
excited or modulated with a second frequency of at least 1 kHz and a second amplitude of
at least 0.1 nm.

B4

9. Raster probe microscope according to claim 3,
characterized in that,
the second raster-probe and/or sample oscillation is a horizontal oscillation with a
frequency of at least 500 Hz and an amplitude of at least 0.1 nm.

B5

11. Raster probe microscope according to claim 3,
characterized by